



DATE: Monday, October 18, 2004

## WEST Search History

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DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ

		<b>Hit Count</b>
<input type="checkbox"/>	L8    l2 and l6	12
<input type="checkbox"/>	L7    l1 and L6	5
<input type="checkbox"/>	L6    deep junction	880
<input type="checkbox"/>	L5    l1 and L4	1
<input type="checkbox"/>	L4    (spaced or spaced apart) near3 ((insulator or insulating) bodies)	369
<input type="checkbox"/>	L3    l1 and l2	1
<input type="checkbox"/>	L2    ((insulator or insulation or insulating or dielectric or oxide) (layer or film)) same (second thickness)	1331
<input type="checkbox"/>	L1    MOSgated or MOS gated or metal oxide semiconductor gated or metal oxide silicon gated	720

END OF SEARCH HISTORY

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# ePHOENIX Reference Manager

Application Number:

No Forms Found for Application Number 10/644,306

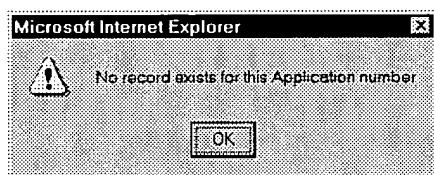
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## US Document Identifiers Search Page

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